



Quality factor analysis of surface-passivated cavities at low gradients applying two level system models

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The native oxides of niobium cause surface losses during cavity operation arising from two-level systems/defects (TLS). These losses dominate the quality factor at low accelerating gradients ($E_{acc} < 0.1$ MV/m). In particular, the amorphous Nb₂O₅ is identified as a prominent host for the TLS. Nb₂O₅ dissociates when the material is baked above 200 °C for several hours in vacuum (the so-called Mid-T Bake), allowing for the modification or reduction of these losses. However, due to the inevitable exposure to air after the annealing, the surface reoxidizes and Nb₂O₅ regrows. When the cavity is already coated with Al₂O₃ or Ta₂O₅ and then subjected to the Mid-T Bake, this subsequent reoxidation of the niobium is inhibited.

It is still unclear how the TLS losses are modified when the surface undergoes a passivating coating, and this study aims at possibly finding a correlation between the different passivating layers.

Herein, we studied the quality factor of several superconducting radio frequency cavities in the low gradient range ($E_{acc} < 0.1$ MV/m) at 1.5 K and analyzed the data using TLS models like the standard TLS model and the non-interacting TLS (one species and two species). Specifically, we used cavities that had undergone the standard “European XFEL” treatment, followed by an atomic layer depositing coating with a passivating layer and the subsequent Mid-T Bake.

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Footnotes

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Author: VENUGOPAL, Rakshith (Deutsches Elektronen-Synchrotron DESY)

Co-authors: Dr DEYU, Getnet Kacha (Universität Hamburg); Mr VOIGE, Marco (Universität Hamburg); KASPRZAK, Karol (Deutsches Elektronen-Synchrotron DESY); WIENCEK, Mateusz (Deutsches Elektronen-Synchrotron DESY); Dr ZIEROLD, Robert (Center for Hybrid Nanostructures); Prof. H. BLICK, Robert (Center for Hybrid Nanostructures); HILLERT, Wolfgang (Universität Hamburg); WEISE, Hans (Deutsches Elektronen-Synchrotron DESY); WENSKAT, Marc (Universität Hamburg)

Presenter: WENSKAT, Marc (Universität Hamburg)

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